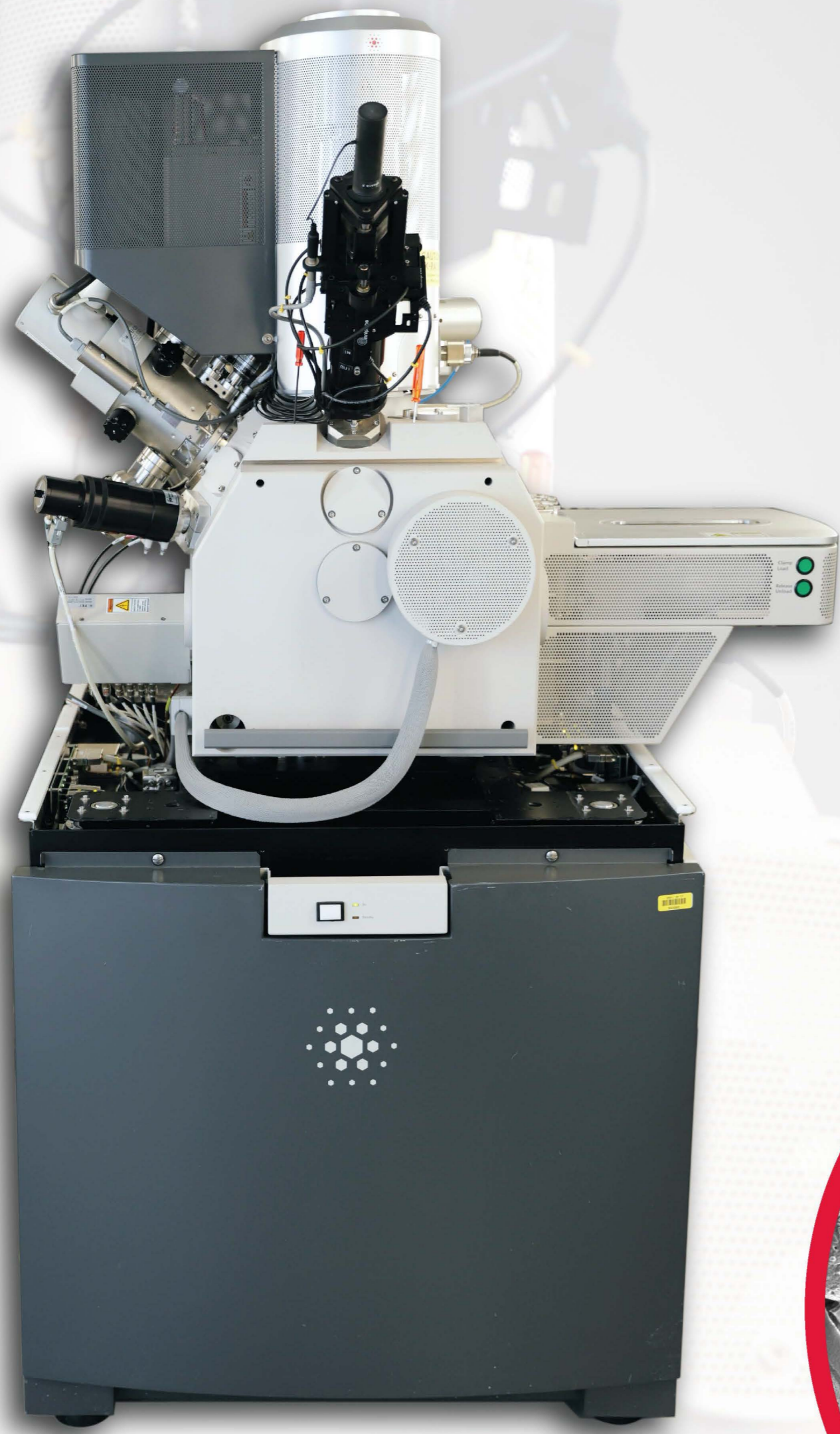
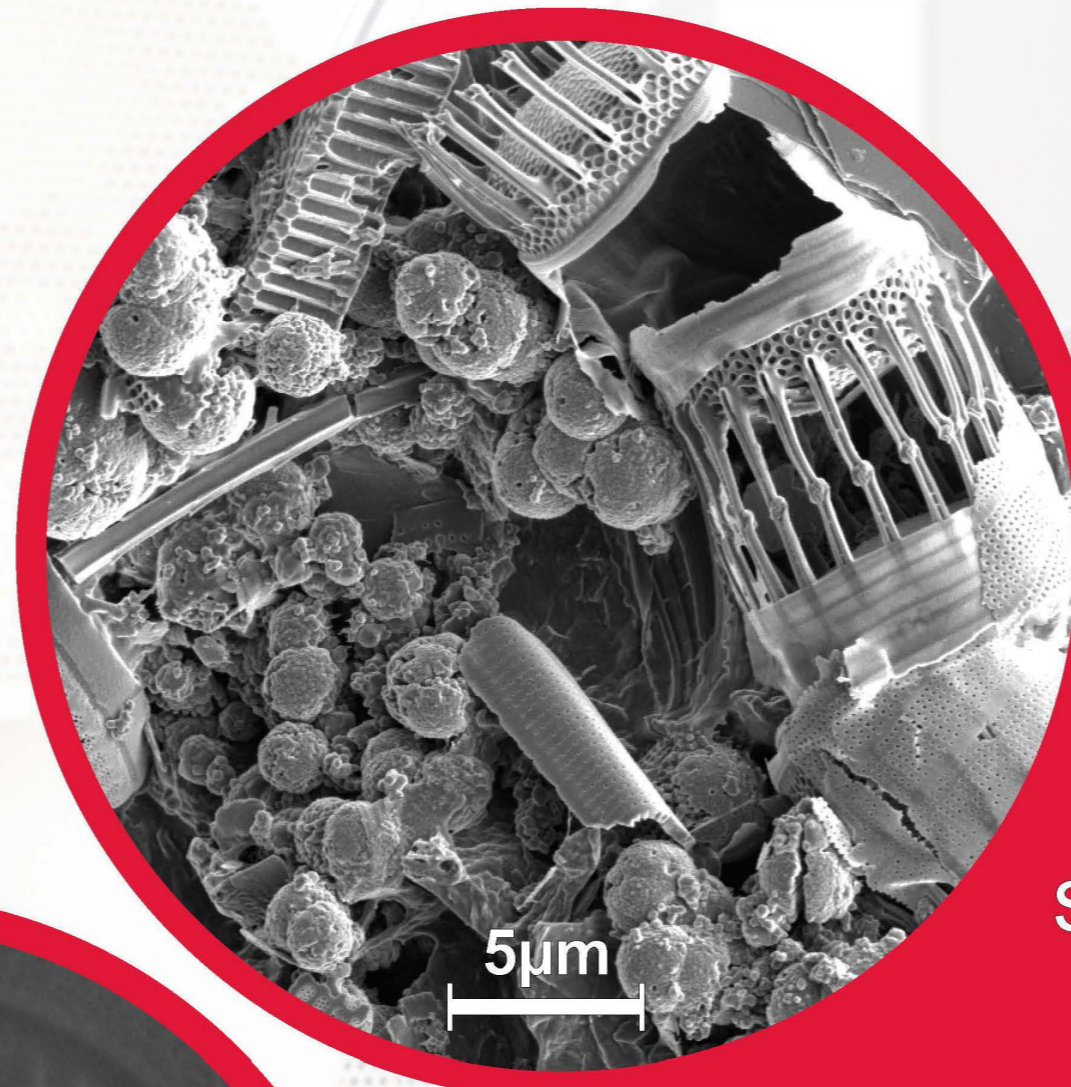


STRATA

Strata 400S Dual Beam



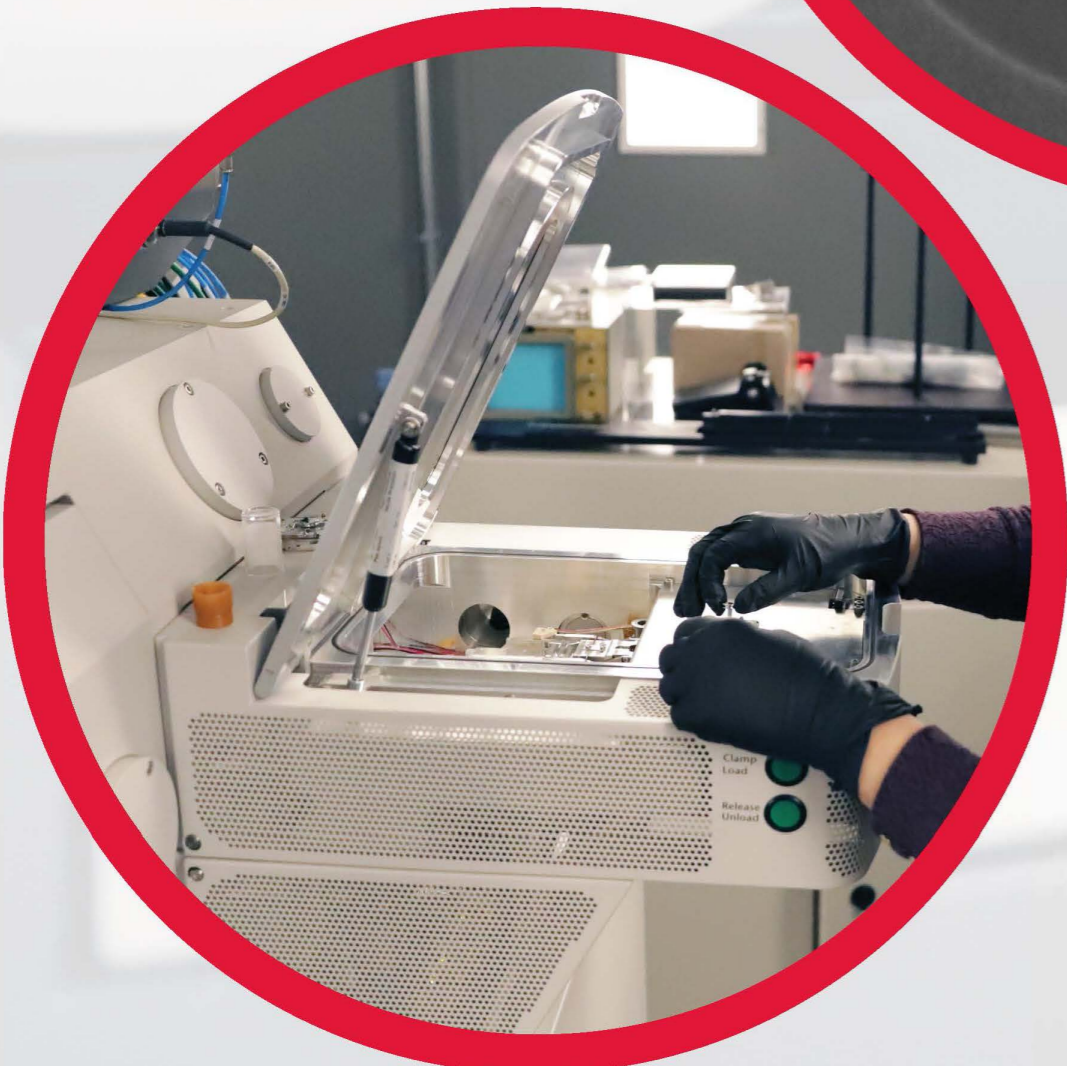
- Dual beam system uses electron beam for imaging and gallium ions for imaging and precise micromachining
- High resolution imaging down to the nanometer level



Titanium oxide spheres mixed with diatom skeletons.



UConn seal ion milled into silicon.



CAMMA
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